

**Search Notes**

Application/Control No.

10/612,299

Examiner

Y. J. Han

Applicant(s)/Patent under  
Reexamination

DINH ET AL.

Art Unit

2838

**SEARCHED**

Class	Subclass	Date	Examiner
323	255		
	256		
	259		
	262		
	264		
	340		
	344		
363	21.06		
	21.14		
	45		
	46		
	47		
	48		
Search	updated	10/27/2006	JH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
See search report		10/29/2006	JH

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PLUS	9/5/2005	jh